

TRSF3232E 3V TO 5.5V Two-Channel RS-232 1Mbit/s Line Driver and Receiver with ±15kV IEC ESD Protection in Small Package

1 Features

- Operates with 3V to 5.5V V_{CC} supply
- Operates up to 1Mbit/s
- Low supply current: 300µA typical
- External capacitors: 4 × 0.1µF
- Accept 5V logic input with 3.3V supply
- Latch-up performance exceeds 100mA Per JESD 78. class II
- ESD protection for RS-232 pins
 - ±15kV Human-Body Model (HBM)
 - ±15kV IEC 61000-4-2 air-gap discharge
 - ±8kV IEC 61000-4-2 contact discharge
- Available in near chip scale QFN (3mmx3mm) package (85% smaller than SOIC-16)

2 Applications

- **Industrial PCs**
- Wired networking
- Data center and enterprise computing
- Battery-powered systems
- **PDAs**
- **Notebooks**
- Palmtop PCs
- Hand-held equipment

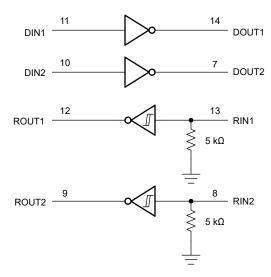
3 Description

The TRSF3232E consists of two line drivers, two line receivers, and a dual charge-pump circuit with ±15kV ESD protection pin to pin (serial-port connection pins, including GND). This device provides the electrical interface between an asynchronous communication controller and the serial-port connector. The charge pump and four small external capacitors allow operation from a single 3V to 5.5V supply. The TRSF3232E operates at data signaling rates up to 1Mbit/s and a driver output slew rate of 14V/µs to 150V/µs.

Package Information

PART NUMBER	PACKAGE ⁽¹⁾	PACKAGE SIZE(2)
	D (SOIC)	9.9mm x 6mm
	DB (SSOP)	6.2mm x 7.8mm
TRSF3232E	DW (SOIC)	10.3 mm x 10.3mm
TROF 5252L	PW (TSSOP)	5mm x 6.4mm
	RGT (VQFN)	3mm x 3mm
	SOT-23-THN (DYY, 16)	4.2mm × 2mm

- For more information, see Section 11.
- The package size (length × width) is a nominal value and includes pins, where applicable.



Logic Diagram (Positive Logic)



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4 Pin Configuration and Functions

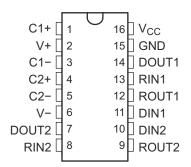


Figure 4-1. D, DB, DW, PW or DYY Package 16-Pin SSOP, TSSOP, or SOT-23-THN (Top View)

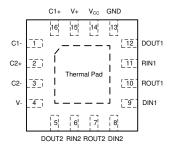


Figure 4-2. RGT, VQFN Package (Top View)

Table 4-1. Pin Functions

	PIN					
NAME	D, DB, DW, PW or DYY	RGT	TYPE ⁽¹⁾	DESCRIPTION		
C1+	1	16	-	Positive lead of C1 capacitor		
V+	2	15	0	Positive charge pump output for storage capacitor only		
C1-	3	1	-	Negative lead of C1 capacitor		
C2+	4	2	-	Positive lead of C2 capacitor		
C2-	5	3	-	Negative lead of C2 capacitor		
V-	6	4	0	Negative charge pump output for storage capacitor only		
DOUT2	7	5	0	RS232 line data output (to remote RS232 system)		
RIN2	8	6	I	RS232 line data input (from remote RS232 system)		
ROUT2	9	7	0	Logic data output (to UART)		
DIN2	10	8	I	Logic data input (from UART)		
DIN1	11	9	I	Logic data input (from UART)		
ROUT1	12	10	0	Logic data output (to UART)		
RIN1	13	11	I	RS232 line data input (from remote RS232 system)		
DOUT1	14	12	0	RS232 line data output (to remote RS232 system)		
GRD	15	13	-	Ground		
V _{CC}	16	14	-	Supply Voltage, Connect to external 3-V to 5.5-V power supply		
Thermal Pad	-	Thermal Pad	-	Exposed thermal pad. Can be connected to GND or left floating.		

⁽¹⁾ Signal Types: I = Input, O = Output, I/O = Input or Output.



5 Specifications

5.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted) see note (1)

				MIN	MAX	UNIT
V _{CC}	Supply voltage range ⁽²⁾			-0.3	6	V
V+	Positive-output supply voltage range ⁽²⁾			-0.3	7	V
V-	Negative-output supply voltage range ⁽²⁾		0.3	-7	V	
V+ – V–	Supply voltage difference ⁽²⁾			13	V	
M	Input voltage range	Drivers		-0.3	6	V
V _I		Receivers		-25	25	V
V	Output voltage range	Drivers		-13.2	13.2	V
Vo	Output voltage range Receivers			-0.3	V _{CC} + 0.3	V
TJ	Operating virtual junction temperature			150	°C	
T _{stg}	Storage temperature range			-65	150	°C

⁽¹⁾ Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

5.2 ESD Ratings

			VALUE	UNIT
\/	V _(ESD) Electrostatic discharge	Human-body model (HBM), per ANSI/ESDA/JEDEC JS-001 ¹ .	±3000	\ \/
V (ESD		Charged-device model (CDM), per JEDEC specification JESD22-C101 ²	±1500	, v

5.3 ESD Protection, Driver

PIN NAME	TEST CONDITIONS	TYP	UNIT
	Human-body model (HBM)	±15	
DOUT1, DOUT2 ⁽²⁾	IEC 61000-4-2 Air-Gap Discharge ⁽¹⁾	±15	kV
	IEC 61000-4-2 Contact Discharge ⁽¹⁾	±8	

⁽¹⁾ For RGT, D and PW packages only: A minimum of 1-μF capacitor is needed between V_{CC} and GND to meet the specified IEC ESD level

5.4 ESD Protection, Receiver

PIN NAME	TEST CONDITIONS	TYP	UNIT
	НВМ	±15	
RIN1, RIN2 ⁽²⁾	IEC 61000-4-2 Air-Gap Discharge (1)	±15	kV
	IEC 61000-4-2 Contact Discharge (1)	±8	

⁽¹⁾ For RGT, D and PW packages only: A minimum of 1-µF capacitor is needed between V_{CC} and GND to meet the specified IEC ESD level.

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⁽²⁾ All voltages are with respect to network GND.

⁽²⁾ For optimized IEC ESD performance for DYY package, the recommendation is to have series resistor (≥ 50Ω), on all logic inputs directly connected to power or ground, to minimize the transient currents going into or out of the logic pins.

⁽²⁾ For optimized IEC ESD performance for DYY package, the recommendation is to have series resistor (≥ 50Ω), on all logic inputs directly connected to power or ground, to minimize the transient currents going into or out of the logic pins.

5.5 Recommended Operating Conditions

See note (1)

				MIN	NOM	MAX	UNIT
	Cumply voltage		V _{CC} = 3.3 V	3	3.3	3.6	V
Supply voltage V _{IH} Driver high-level input voltage DIN V _{IL} Driver low-level input voltage V _I Driver input voltage Receiver input voltage	V _{CC} = 5 V	4.5	5	5.5	v		
\/	Driver high level input veltage	DIN	V _{CC} = 3.3 V	2			V
VIH	Driver high-lever input voitage	DIN	V _{CC} = 5 V	2.4			v
V _{IL}	Driver low-level input voltage		DIN			8.0	V
.,	Driver input voltage		DIN	0		5.5	V
VI	Receiver input voltage		•	-25		25	v
_	Operating free-air temperature		TRSF3232EI	-40		85	°C
T _A			TRSF3232EC	0		70	

⁽¹⁾ Test conditions are C1–C4 = 0.1 μ F at V_{CC} = 3.3 V \pm 0.3 V; C1 = 0.047 μ F, C2–C4 = 0.33 μ F at V_{CC} = 5 V \pm 0.5 V (see Figure 8-1).

5.6 Thermal Information

				TRSF	3232E			
THERMAL METRIC(1)		PW (TSSOP)	D (SOIC)	DW (SOIC)	DB (SSOP)	RGT (VQFN)	DYY (SOT-23-THN)	UNIT
		16 Pins	16 Pins	16 Pins	16 Pins	16 Pins	16 Pins	
R _{θJA}	Junction-to-ambient thermal resistance	108.2	85.9	57	46	48.8	106.2	°C/W
R _{θJC(top)}	Junction-to-case (bottom) thermal resistance	39.0	43.1	33.5	36.2	55.8	47.4	°C/W
R _{θJB}	Junction-to-board thermal resistance	54.4	44.5	37.1	43.8	23.2	44.7	°C/W
Ψ лт	Junction-to-top characterization parameter	3.3	10.1	7.5	4.2	1.7	1.7	°C/W
Ψ ЈВ	Junction-to-board characterization parameter	53.8	44.1	37.1	42.9	23.2	43.7	°C/W
R _{θJC(bot)}	Junction-to-case (bottom) thermal resistance	N/A	N/A	N/A	N/A	9.0	N/A	°C/W

⁽¹⁾ For more information about traditional and new thermal metrics, see the Semiconductor and IC package thermal metrics application

5.7 Electrical Characteristics

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

	PARAMETER	TEST CONDITIONS ⁽¹⁾		MIN	TYP ⁽²⁾	MAX	UNIT
I _{CC}	Supply current	No load,	V_{CC} = 3.3 V or 5 V		0.3	1	mA

Test conditions are C1–C4 = 0.1 μ F at V_{CC} = 3.3 V \pm 0.3 V; C1 = 0.047 μ F, C2–C4 = 0.33 μ F at V_{CC} = 5 V \pm 0.5 V (see Figure 8-1). All typical values are at V_{CC} = 3.3 V or V_{CC} = 5 V, and T_A = 25°C.



5.8 Electrical Characteristics, Driver

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

	PARAMETER	TEST CONDITION	S ⁽¹⁾	MIN	TYP ⁽²⁾	MAX	UNIT
V _{OH}	High-level output voltage	DOUT at $R_L = 3 \text{ k}\Omega$ to GND,	DIN = GND	5	5.5		V
V _{OL}	Low-level output voltage	DOUT at $R_L = 3 \text{ k}\Omega$ to GND,	DIN = V _{CC}	-5	-5.4		V
I _{IH}	High-level input current	V _I = V _{CC}			±0.01	±1	μA
I _{IL}	Low-level input current	V _I at GND		±0.01	±1	μA	
		V _{CC} = 3.6 V, V _O = 0 V			±35	±60	
I _{OS}	Short-circuit output current		RGT package only		±35	±60	mA
(3)	Chort-on out output current	$V_{CC} = 5.5 \text{ V}, V_{O} = 0 \text{ V}$	D, DB, DW, PW packages		±35	±90	
r _o	Output resistance	V _{CC} , V+, and V– = 0 V,	V _O = ±2 V	300	10M		Ω

- Test conditions are C1–C4 = 0.1 μ F at V_{CC} = 3.3 V ± 0.3 V; C1 = 0.047 μ F, C2–C4 = 0.33 μ F at V_{CC} = 5 V ± 0.5 V (see Figure 8-1). (1)
- (2)
- All typical values are at $V_{CC} = 3.3 \text{ V}$ or $V_{CC} = 5 \text{ V}$, and $T_A = 25 ^{\circ}\text{C}$. Short-circuit durations should be controlled to prevent exceeding the device absolute power dissipation ratings, and not more than one output should be shorted at a time.

5.9 Electrical Characteristics, Receiver

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

	PARAMETER	TEST CONDITIONS ⁽¹⁾	MIN	TYP ⁽²⁾	MAX	UNIT
V _{OH}	High-level output voltage	I _{OH} = -1 mA	V _{CC} – 0.6	V _{CC} – 0.1		٧
V _{OL}	Low-level output voltage	I _{OL} = 1.6 mA			0.4	V
\ <u>\</u>	Positive-going input threshold	V _{CC} = 3.3 V		1.5	2.4	V
V _{IT+}	voltage	V _{CC} = 5 V		1.8	2.4	v
V-	Negative-going input threshold	V _{CC} = 3.3 V	0.6	1.2		٧
V _{IT}	voltage	V _{CC} = 5 V	0.8	1.5		v
V _{hys}	Input hysteresis (V _{IT+} – V _{IT-})			0.3		V
rį	Input resistance	V _I = ±3 V to ±25 V	3	5	7	kΩ

- Test conditions are C1–C4 = 0.1 μF at V_{CC} = 3.3 V ± 0.3 V; C1 = 0.047 μF, C2–C4 = 0.33 μF at V_{CC} = 5 V ± 0.5 V (see Figure 8-1).
- All typical values are at V_{CC} = 3.3 V or V_{CC} = 5 V, and T_A = 25°C.

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5.10 Switching Characteristics, Driver

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

	<u> </u>	TEST CON	IDITIONS ⁽¹⁾	MIN	TYP ⁽²⁾ MA	UNIT
	Maximum data rate	$R_L = 3 k\Omega$	C _L = 250 pF,V _{CC} = 3 V to 4.5 V	1000		kbit/s
	(see Figure 6-1)		C _L = 1000 pF,V _{CC} = 3.5 V to 5.5 V	1000		KDIUS
		C_L = 1000 pF, R_L = 3 k Ω , V_{cc} = 5 V (see Figure 6-2)	RGT package only	70		
t _{sk(p)}	Pulse skew ⁽³⁾	C_L = 150 pF to 2500 pF, R_L = 3 k Ω to 7 k Ω (see Figure 6-2)	D, DB, DW, PW packages	300		ns
SR(tr)	Slew rate, transition region (see Figure 6-1)	$R_L = 3 \text{ k}\Omega \text{ to } 7 \text{ k}\Omega, C_L = 15$	$50 \text{ pF to } 1000 \text{ pF, V}_{CC} = 3.3$	14	15	O V/µs

- Test conditions are C1–C4 = 0.1 μ F at V_{CC} = 3.3 $V \pm 0.3 V$; C1 = 0.047 μ F, C2–C4 = 0.33 μ F at V_{CC} = 5 $V \pm 0.5 V$ (see Figure 8-1).
- All typical values are at V_{CC} = 3.3 V or V_{CC} = 5 V, and T_A = 25°C. Pulse skew is defined as $|t_{PLH} t_{PHL}|$ of each channel of the same device.

5.11 Switching Characteristics, Reveiver

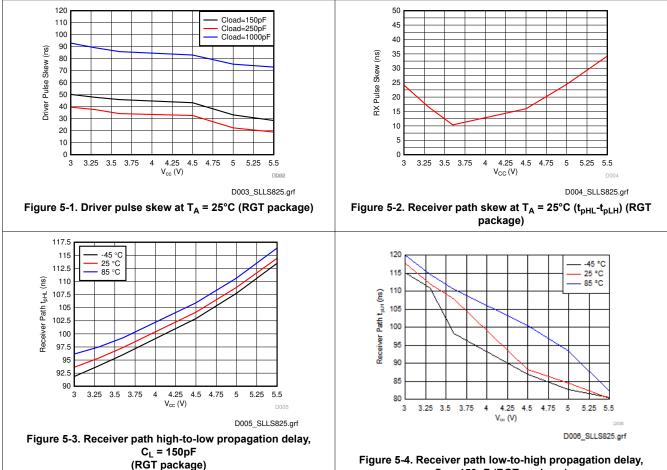
over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

		TEST CON	IDITIONS ⁽¹⁾	MIN TYP ⁽²⁾ MAX	UNIT
t _{PLH}	Propagation delay time, low- to	C ₁ = 150 pF	RGT package	85	ns
	high-level output	С[- 150 рі	D, DB, DW, PW packages	300	- 115
, Pro	Propagation delay time, high- to	C ₁ = 150 pF	RGT package	110	ne
T _{PHL}	low-level output	С_ = 130 рг	D, DB, DW, PW packages	300	ns
t	Pulse skew ⁽³⁾	RGT package		25	ns
t _{sk(p)}		D, DB, DW, PW packages		300	- IIS

- Test conditions are C1–C4 = 0.1 μ F at V_{CC} = 3.3 V ± 0.3 V; C1 = 0.047 μ F, C2–C4 = 0.33 μ F at V_{CC} = 5 V ± 0.5 V (see Figure 8-1).
- (2)
- All typical values are at V_{CC} = 3.3 V or V_{CC} = 5 V, and T_A = 25°C. Pulse skew is defined as $|t_{PLH} t_{PHL}|$ of each channel of the same device.

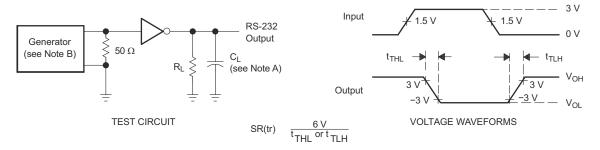


5.12 Typical Characteristics



C_L = 150pF (RGT package)

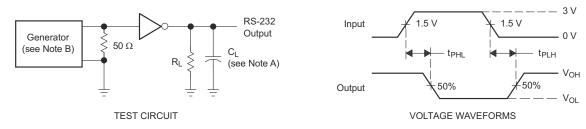
6 Parameter Measurement Information



NOTES: A. C_L includes probe and jig capacitance.

B. The pulse generator has the following characteristics: PRR = 250 kbit/s, $Z_0 = 50 \Omega$, 50% duty cycle, $t_f \le 10$ ns, $t_f \le 10$ ns.

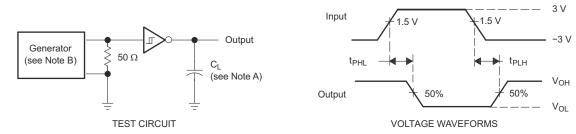
Figure 6-1. Driver Slew Rate



NOTES: A. C_L includes probe and jig capacitance.

B. The pulse generator has the following characteristics: PRR = 250 kbit/s, $Z_O = 50 \Omega$, 50% duty cycle, $t_r \le 10$ ns, $t_f \le 10$ ns.

Figure 6-2. Driver Pulse Skew



NOTES: A. C_L includes probe and jig capacitance.

B. The pulse generator has the following characteristics: $Z_0 = 50 \Omega$, 50% duty cycle, $t_r \le 10$ ns, $t_f \le 10$ ns.

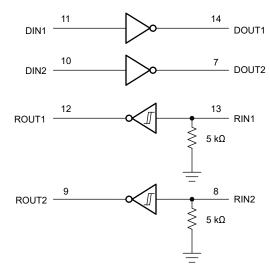
Figure 6-3. Receiver Propagation Delay Times

7 Detailed Description

7.1 Overview

The TRSF3232E device consists of two line drivers, two line receivers, and a dual charge-pump circuit with ±15kV IEC ESD protection between serial-port connection terminals and GND. The device meets the requirements of TIA/EIA-232-F and provides the electrical interface between an asynchronous communication controller and the serial-port connector. The charge pump and four small external capacitors allow operation from one 3V to 5.5V supply. The device operates at data signaling rates up to 1Mbps and a maximum of 150V/µs driver output slew rate. Outputs are protected against shorts to ground.

7.2 Functional Block Diagram



7.3 Feature Description

7.3.1 Power

The power block increases, inverts, and regulates voltage at V+ and V- pins using a charge pump that requires four external capacitors.

7.3.2 RS232 Driver

Two drivers interface the standard logic level to RS232 levels. Both DIN inputs must be valid high or low.

7.3.3 RS232 Receiver

Two receivers interface RS232 levels to standard logic levels. An open input results in a high output on ROUT. Each RIN input includes an internal standard RS232 load.

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7.4 Device Functional Modes

Table 7-1. Each Driver

INPUT DIN ⁽¹⁾	OUTPUT DOUT
L	Н
Н	L

(1) H = high level, L = low level

Table 7-2. Each Receiver

INPUT RIN ⁽¹⁾	OUTPUT ROUT							
L	н							
Н	L							
Open	Н							

(1) H = high level, L = low level,Open = input disconnected or connected driver off

7.4.1 V_{CC} Powered by 3V to 5.5V

The device is in normal operation.

7.4.2 V_{CC} Unpowered, $V_{CC} = 0V$

When the TRS3232 device is unpowered, it can be safely connected to an active remote RS232 device.



8 Application and Implementation

Note

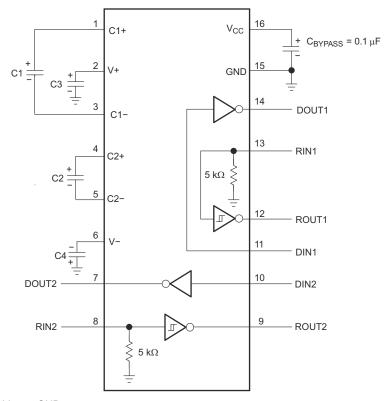
Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes, as well as validating and testing their design implementation to confirm system functionality.

8.1 Application Information

The TRSF3232E device is designed to convert single-ended signals into RS232-compatible signals, and vice-versa. This device can be used in any application where an RS232 line driver or receiver is required.

ROUT and DIN connect to UART or general-purpose logic lines. RIN and DOUT lines connect to a RS232 connector or cable.

8.2 Typical Application



A. C3 can be connected to V_{CC} or GND.

Figure 8-1. Typical Operating Circuit and Capacitor Values

Table 8-1. VCC vs Capacitor Values

V _{CC}	C1	C2, C3, C4			
3.3V ± 0.3V	0.1µF	0.1µF			
5V ± 0.5V	0.047µF	0.33µF			
3V to 5.5V	0.1µF	0.47µF			

Product Folder Links: TRSF3232E

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8.2.1 Design Requirements

- Recommended V_{CC} is 3.3V or 5V
 - 3V to 5.5V is also possible
- Maximum recommended bit rate is 250kbites

8.2.2 Detailed Design Procedure

All DIN inputs must be connected to valid low or high logic levels. Select capacitor values based on VCC level for best performance.

8.2.3 Application Performance Plots

VCC must be between 3 V and 5.5 V. Charge pump capacitors must be chosen using Table 8-1

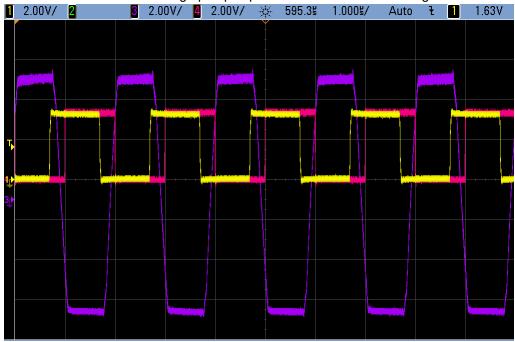


Figure 8-2. 1Mbps timing waveform from driver input to receiver output loopback. DOUT to RIN trace is in purple, DIN trace is in yellow and ROUT trace is in pink

8.3 Power Supply Recommendations

The supply voltage, V_{CC}, should be between 3V and 5.5V. Select the charge-pump capacitors using Table 8-1.

8.4 Layout

8.4.1 Layout Guidelines

Keep the external capacitor traces short, specifically on the C1 and C2 nodes that have the fastest rise and fall times.



8.4.2 Layout Example

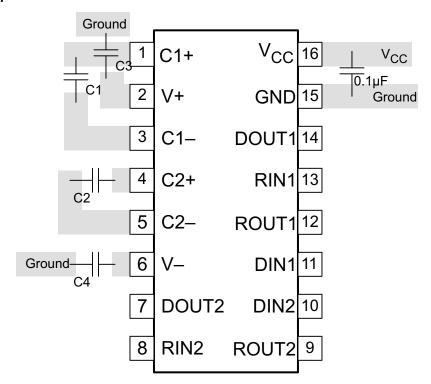


Figure 8-3. Layout Diagram

9 Device and Documentation Support

TI offers an extensive line of development tools. Tools and software to evaluate the performance of the device, generate code, and develop solutions are listed below.

9.1 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. Click on *Notifications* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

9.2 Support Resources

TI E2E[™] support forums are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

Linked content is provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

9.3 Trademarks

TI E2E[™] is a trademark of Texas Instruments.

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9.4 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

9.5 Glossary

TI Glossary

This glossary lists and explains terms, acronyms, and definitions.

10 Revision History

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

 Cha 	nged the Device Information table to the Package Information tabletable	1
 Add 	ed the SOT-23-THN (DYY) package to the data sheet	1
 Add 	ed Note 2 to the ESD Protection, Driver	4
	ed Note 2 to the ESD Protection, Receiver	
Change	es from Revision A (December 2020) to Revision B (June 2021)	Page
	es from Revision A (December 2020) to Revision B (June 2021) ed Applications: Industrial PCs, Wired networking, and Data center and enterprise computin	
• Add	, , , , , , , , , , , , , , , , , , , ,	ıg 1
AddCha	ed Applications: Industrial PCs, Wired networking, and Data center and enterprise computin	ng1 ackages4

Changes from Revision * (August 2007) to Revision A (December 2020)

Changes from Revision B (June 2021) to Revision C (December 2024)

Page

Page

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TRSF3232E

SLLS825C - AUGUST 2007 - REVISED DECEMBER 2024



•	Added Note to the ESD Protection, Receiver	.4
	Added t _{sk(p)} row for RGT package in the Switching Characteristics, Driver	
	Added t _{Pl H} and t _{PHI} rows for RGT package in the Switching Characteristics, Reveiver	
	Added t _{sk(p)} row for RGT package in the Switching Characteristics, Reveiver	

11 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

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PACKAGING INFORMATION

Orderable part number	Status (1)	Material type	Package Pins	Package qty Carrier	RoHS (3)	Lead finish/ Ball material	MSL rating/ Peak reflow	Op temp (°C)	Part marking (6)
TRSF3232ECDBR	Active	Production	SSOP (DB) 16	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	0 to 70	RT32EC
TRSF3232ECDBR.A	Active	Production	SSOP (DB) 16	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	0 to 70	RT32EC
TRSF3232ECDR	Active	Production	SOIC (D) 16	2500 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	0 to 70	TRSF3232EC
TRSF3232ECDR.A	Active	Production	SOIC (D) 16	2500 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	0 to 70	TRSF3232EC
TRSF3232ECDWR	Obsolete	Production	SOIC (DW) 16	-	-	Call TI	Call TI	0 to 70	TRSF3232EC
TRSF3232ECPWR	Active	Production	TSSOP (PW) 16	2000 LARGE T&R	Yes	NIPDAU SN	Level-1-260C-UNLIM	0 to 70	RT32EC
TRSF3232ECPWR.A	Active	Production	TSSOP (PW) 16	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	0 to 70	RT32EC
TRSF3232EID	Obsolete	Production	SOIC (D) 16	-	-	Call TI	Call TI	-40 to 85	TRSF3232EI
TRSF3232EIDBR	Active	Production	SSOP (DB) 16	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	RT32EI
TRSF3232EIDBR.A	Active	Production	SSOP (DB) 16	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	RT32EI
TRSF3232EIDR	Active	Production	SOIC (D) 16	2500 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	TRSF3232EI
TRSF3232EIDR.A	Active	Production	SOIC (D) 16	2500 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	TRSF3232EI
TRSF3232EIDRG4	Active	Production	SOIC (D) 16	2500 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	TRSF3232EI
TRSF3232EIDRG4.A	Active	Production	SOIC (D) 16	2500 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	TRSF3232EI
TRSF3232EIDW	Active	Production	SOIC (DW) 16	40 TUBE	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	TRSF3232EI
TRSF3232EIDW.A	Active	Production	SOIC (DW) 16	40 TUBE	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	TRSF3232EI
TRSF3232EIDWR	Active	Production	SOIC (DW) 16	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	TRSF3232EI
TRSF3232EIDWR.A	Active	Production	SOIC (DW) 16	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	TRSF3232EI
TRSF3232EIDYYR	Active	Production	SOT-23-THIN (DYY) 16	3000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	RT32EI
TRSF3232EIDYYR.A	Active	Production	SOT-23-THIN (DYY) 16	3000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	RT32EI
TRSF3232EIPWR	Active	Production	TSSOP (PW) 16	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	RT32EI
TRSF3232EIPWR.A	Active	Production	TSSOP (PW) 16	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	RT32EI
TRSF3232EIPWRG4	Active	Production	TSSOP (PW) 16	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	RT32EI
TRSF3232EIPWRG4.A	Active	Production	TSSOP (PW) 16	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	RT32EI
TRSF3232EIRGTR	Active	Production	VQFN (RGT) 16	3000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	F3232
TRSF3232EIRGTR.A	Active	Production	VQFN (RGT) 16	3000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	F3232

⁽¹⁾ Status: For more details on status, see our product life cycle.



PACKAGE OPTION ADDENDUM

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- (2) Material type: When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.
- (3) RoHS values: Yes, No, RoHS Exempt. See the TI RoHS Statement for additional information and value definition.
- (4) Lead finish/Ball material: Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.
- (5) MSL rating/Peak reflow: The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.
- (6) Part marking: There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

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TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
TRSF3232ECDBR	SSOP	DB	16	2000	330.0	16.4	8.35	6.6	2.4	12.0	16.0	Q1
TRSF3232ECDR	SOIC	D	16	2500	330.0	16.4	6.5	10.3	2.1	8.0	16.0	Q1
TRSF3232ECPWR	TSSOP	PW	16	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1
TRSF3232EIDBR	SSOP	DB	16	2000	330.0	16.4	8.35	6.6	2.4	12.0	16.0	Q1
TRSF3232EIDR	SOIC	D	16	2500	330.0	16.4	6.5	10.3	2.1	8.0	16.0	Q1
TRSF3232EIDRG4	SOIC	D	16	2500	330.0	16.4	6.5	10.3	2.1	8.0	16.0	Q1
TRSF3232EIDWR	SOIC	DW	16	2000	330.0	16.4	10.75	10.7	2.7	12.0	16.0	Q1
TRSF3232EIDYYR	SOT-23- THIN	DYY	16	3000	330.0	12.4	4.8	3.6	1.6	8.0	12.0	Q3
TRSF3232EIPWR	TSSOP	PW	16	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1
TRSF3232EIPWRG4	TSSOP	PW	16	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1
TRSF3232EIRGTR	VQFN	RGT	16	3000	330.0	12.4	3.3	3.3	1.1	8.0	12.0	Q2



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*All dimensions are nominal

7 til dilliciolorio are nominal							
Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
TRSF3232ECDBR	SSOP	DB	16	2000	353.0	353.0	32.0
TRSF3232ECDR	SOIC	D	16	2500	353.0	353.0	32.0
TRSF3232ECPWR	TSSOP	PW	16	2000	356.0	356.0	35.0
TRSF3232EIDBR	SSOP	DB	16	2000	353.0	353.0	32.0
TRSF3232EIDR	SOIC	D	16	2500	353.0	353.0	32.0
TRSF3232EIDRG4	SOIC	D	16	2500	353.0	353.0	32.0
TRSF3232EIDWR	SOIC	DW	16	2000	350.0	350.0	43.0
TRSF3232EIDYYR	SOT-23-THIN	DYY	16	3000	336.6	336.6	31.8
TRSF3232EIPWR	TSSOP	PW	16	2000	353.0	353.0	32.0
TRSF3232EIPWRG4	TSSOP	PW	16	2000	353.0	353.0	32.0
TRSF3232EIRGTR	VQFN	RGT	16	3000	367.0	367.0	35.0

PACKAGE MATERIALS INFORMATION

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TUBE



*All dimensions are nominal

Device	Package Name	Package Type	Pins	SPQ	L (mm)	W (mm)	T (µm)	B (mm)
TRSF3232EIDW	DW	SOIC	16	40	506.98	12.7	4826	6.6
TRSF3232EIDW.A	DW	SOIC	16	40	506.98	12.7	4826	6.6



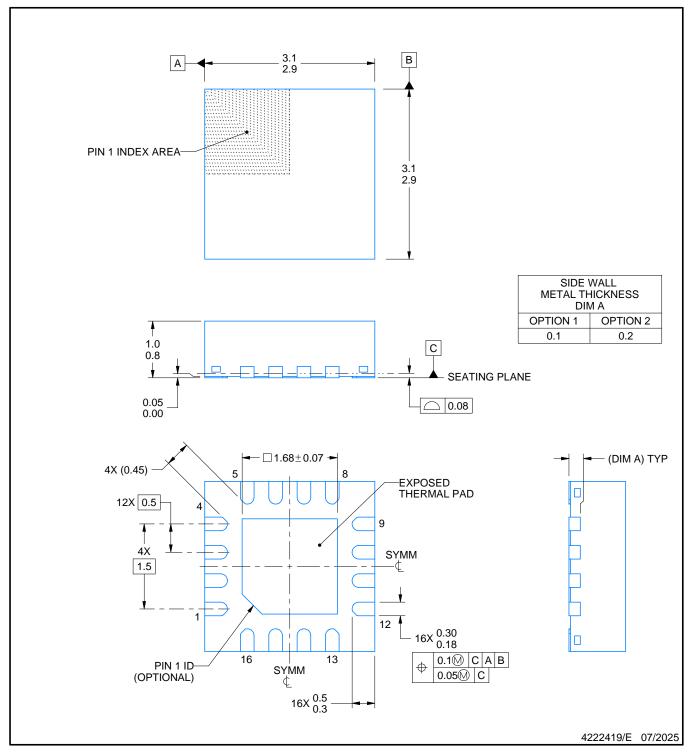
Images above are just a representation of the package family, actual package may vary. Refer to the product data sheet for package details.







PLASTIC QUAD FLATPACK - NO LEAD

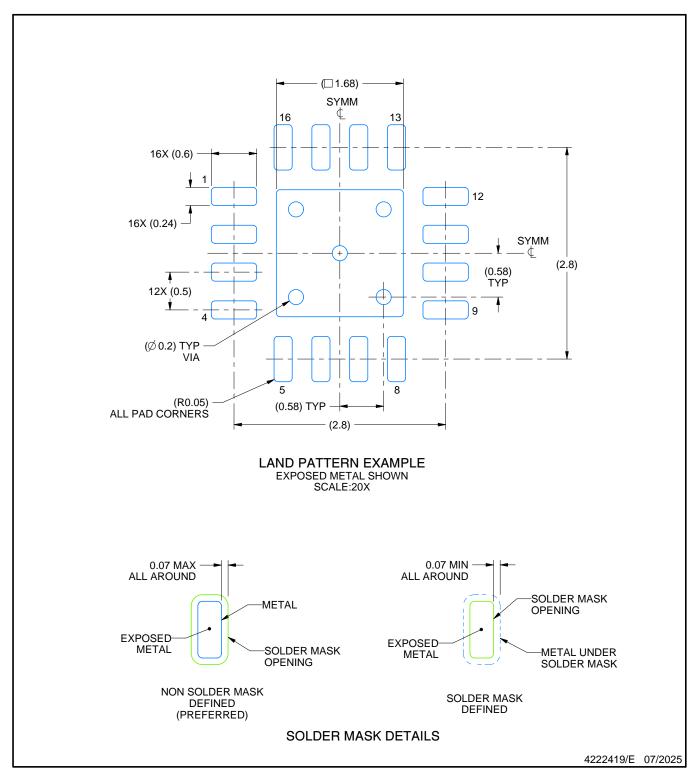


NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
 2. This drawing is subject to change without notice.
- 3. The package thermal pad must be soldered to the printed circuit board for thermal and mechanical performance.



PLASTIC QUAD FLATPACK - NO LEAD

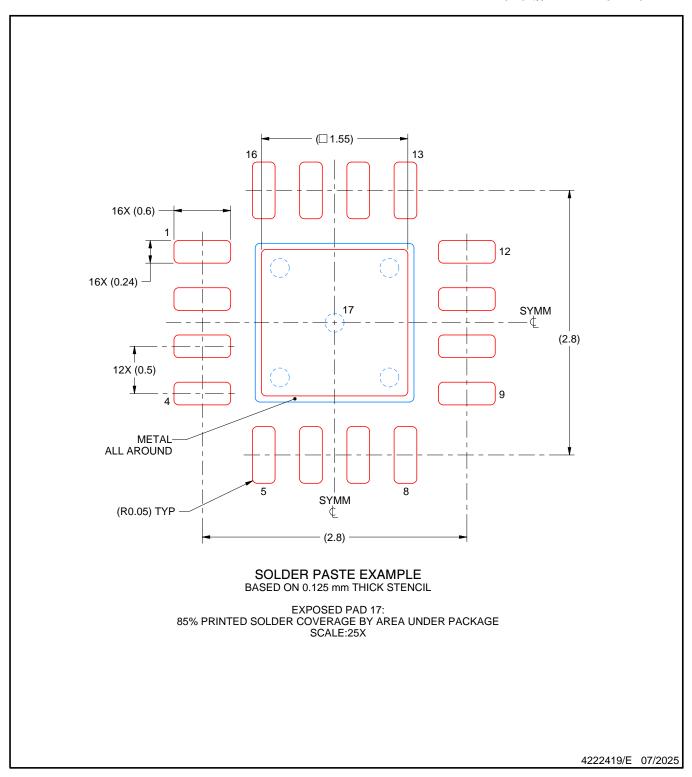


NOTES: (continued)

- 4. This package is designed to be soldered to a thermal pad on the board. For more information, see Texas Instruments literature number SLUA271 (www.ti.com/lit/slua271).
- Vias are optional depending on application, refer to device data sheet. If any vias are implemented, refer to their locations shown on this view. It is recommended that vias under paste be filled, plugged or tented.



PLASTIC QUAD FLATPACK - NO LEAD



NOTES: (continued)

6. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.



D (R-PDS0-G16)

PLASTIC SMALL OUTLINE



NOTES:

- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.006 (0,15) each side.
- Body width does not include interlead flash. Interlead flash shall not exceed 0.017 (0,43) each side.
- E. Reference JEDEC MS-012 variation AC.







NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
 4. Reference JEDEC registration MO-150.





NOTES: (continued)

- 5. Publication IPC-7351 may have alternate designs.
- 6. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



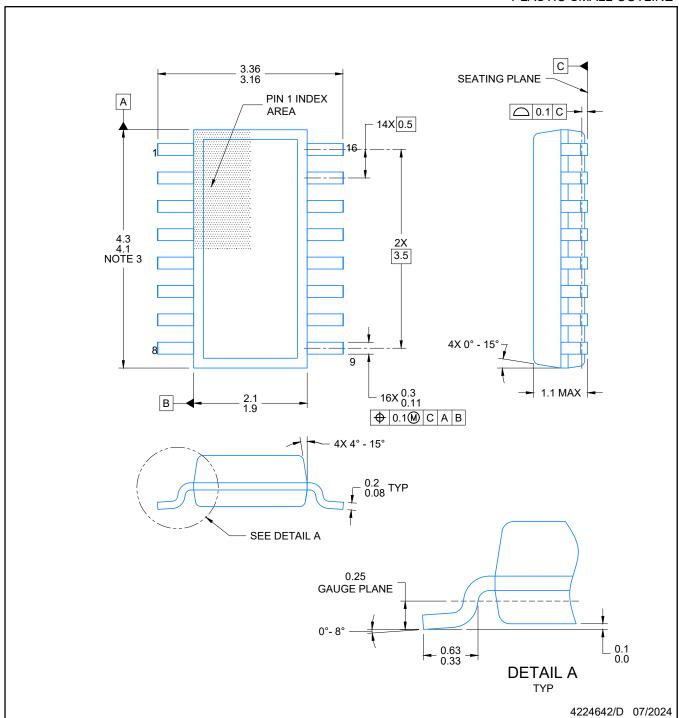


NOTES: (continued)

- 7. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 8. Board assembly site may have different recommendations for stencil design.



PLASTIC SMALL OUTLINE

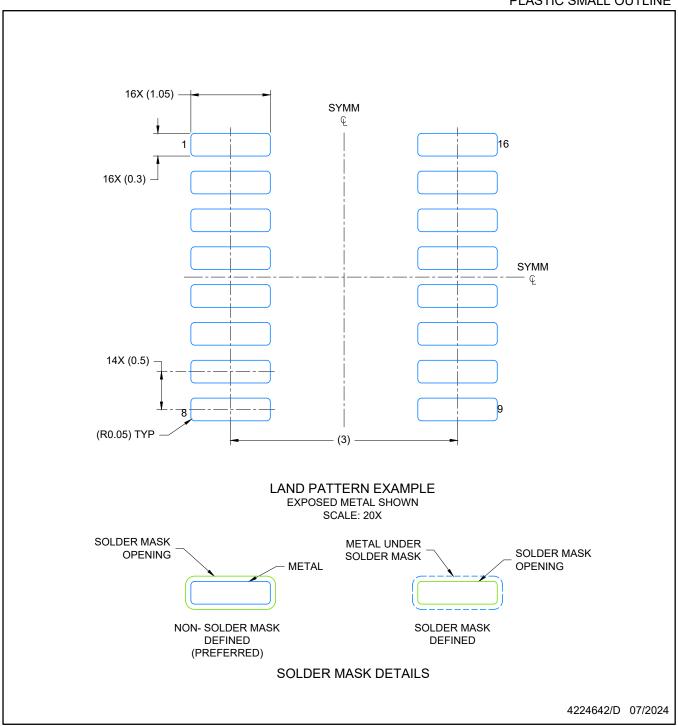


NOTES:

- All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
- 2. This drawing is subject to change without notice.
- 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.15 per side
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.50 per side.
- 5. Reference JEDEC Registration MO-345, Variation AA



PLASTIC SMALL OUTLINE

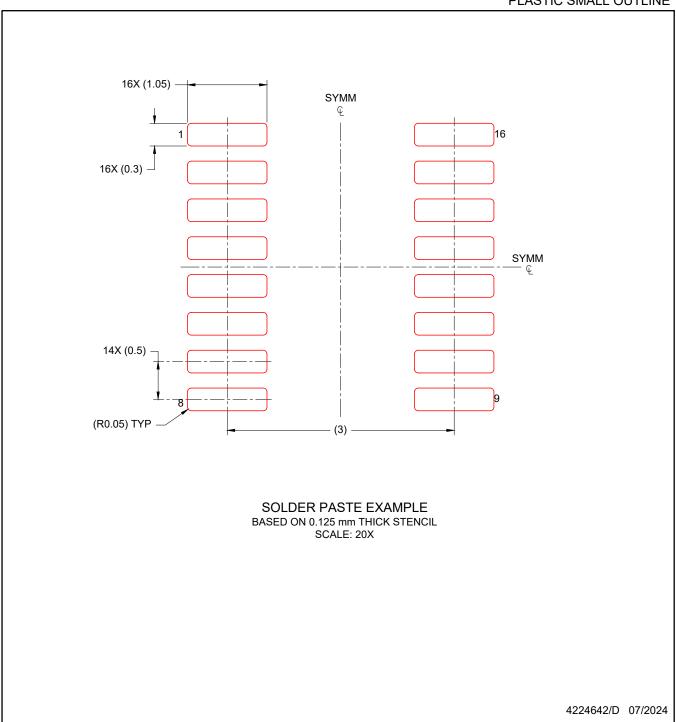


NOTES: (continued)

- 6. Publication IPC-7351 may have alternate designs.
- 7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



PLASTIC SMALL OUTLINE



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



7.5 x 10.3, 1.27 mm pitch

SMALL OUTLINE INTEGRATED CIRCUIT

This image is a representation of the package family, actual package may vary. Refer to the product data sheet for package details.





SOIC



NOTES:

- 1. All linear dimensions are in millimeters. Dimensions in parenthesis are for reference only. Dimensioning and tolerancing
- per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.15 mm, per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm, per side.
- 5. Reference JEDEC registration MS-013.



SOIC



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SOIC



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.







NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
- 5. Reference JEDEC registration MO-153.





NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.





NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



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